

Abstracts

On-Wafer Testing of MMIC with Monolithically Integrated Photoconductive Switches

S.L. Huang, E.A. Chauchard, C.H. Lee, T.T. Lee, H.-L.A. Hung and T. Joseph. "On-Wafer Testing of MMIC with Monolithically Integrated Photoconductive Switches." 1992 MTT-S International Microwave Symposium Digest 92.2 (1992 Vol. II [MWSYM]): 661-664.

This is the first report that photoconductive (PC) test structures have been fabricated monolithically with MMIC amplifiers for microwave characterization using an optical technique. Good agreement has been obtained between the measured results and those obtained from a conventional network analyzer.

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